Appl. No. 10/657,602

Amdt. dated 2/25/05

Reply to Office action of January 10, 2005

CLAIM AMENDMENTS

This listing of claims will replace all prior versions, and listings, of claims in the application:

Listing of Claims:

Claim 1 (currently amended). A circuit, connected for operation as a FIB sensor of a smart card IC, for detecting a focused ion beam attack, comprising:

a memory cell;

an antenna for detecting an FIB attack connected to said memory cell;

a driver circuit; and

a capacitance connected between said memory cell and said driver circuit, for isolating said driver circuit from said antenna.

Claim 2 (original). The circuit according to claim 1, wherein said memory cell is a memory cell selected from the group consisting of a floating gate cell, an EEPROM cell, a flash cell, and a SONOS cell.

Appl. No. 10/657,602 Amdt. dated 2/25/05

Reply to Office action of January 10, 2005

Claim 3 (original). The circuit according to claim 1, wherein said memory cell comprises an electrically conductive electrode over a silicon area.

Claim 4 (original). The circuit according to claim 1, wherein said memory cell is one of two memory cells connected to said antenna and isolated from said driver circuit by said capacitance.

Claim 5 (canceled).